



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR § 1.56, § 1.97, and § 1.98 FORM PTO-1449		APPLICATION SERIAL NO.: 10/623,364	ATTORNEY DOCKET NO.: 38203-6215
		APPLICANTS: A. Smith et al.	
		FILING DATE: July 18, 2003	GROUP ART UNIT: 2872
Sheet 1 of 1			

U.S. PATENT DOCUMENTS						
*EX'R INITIAL	*REF. #	PATENT NUMBER	DATE	NAME	U.S. CLASS/ SUBCLASS	FILING DATE (if appropriate)
PK	A*	5,828,455	10/27/1998	Smith et al.	356/354	03/07/1997
PLC	B*	5,978,085	11/02/1999	Smith et al.	356/354	10/23/1997

FOREIGN PATENT DOCUMENTS					
*EX'R INITIAL	*REF. #	DOCUMENT NO.	DATE	COUNTRY	TRANSLATION (YES/NO)
		NONE			

NON-PATENT DOCUMENTS					
*EX'R INITIAL	*REF. #	CITATION (Author, Article Title, Journal/Book Title, Date, Pertinent Pages, etc.)			
PLC	C	Y. Shiode et al., "Method of Zernike Coefficients Extraction for Optics Aberration Measurement", SPIE, Vol. 4691, 2002, pp. 1453-1464.			

EXAMINER'S SIGNATURE 	DATE CONSIDERED 5/26/04
<p>* EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609. Line through citation if not in conformance and not considered. <i>Include copy of this form in next communication to applicant.</i></p> <p>* If an asterisk is placed beside the reference number, a copy is not provided because the reference was previously cited by or submitted to the PTO in a prior application that is identified in the statement and relied upon for an earlier filing date under 35 U.S.C. 120. 37 C.F.R. 1.98(d), or a copy is not provided per the Office waiver published in the Official Gazette on August 5, 2003.</p>	
TITLE: IN-SITU INTERFEROMETER ARRANGEMENT	